

<b>Notice of References Cited</b>	Application/Control No. 10/701,156	Applicant(s)/Patent Under Reexamination IWATA, YUJI	
	Examiner Shih-wen Hsieh	Art Unit 2861	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,439,712	08-2002	Mizutani et al.	347/102
*	B	US-5,847,723	12-1998	Akahira et al.	347/14
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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